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# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application of

Jyoti Kiron BHARDWAJ

Attn: Applications Branch

Serial No. [NEW]

Attorney Docket No.: WLJ.059

Filed: November 3, 2000

Title: GAS GENERATION SYSTEM

#### PRELIMINARY AMENDMENT

Honorable Commissioner of Patents and Trademarks, Washington, D.C. 20231

Sir:

Preliminary to the examination of the above-identified application, please enter the following amendments and consider the following remarks:

# IN THE CLAIMS:

Please cancel claims 7-9 without prejudice.

Please amend the claims as follows:

Claim 3, line 1, delete "or claim ";

line 2, delete "2".

Claim 4, line 1, delete "or claim";

line 2, delete "2".

Claim 5, line 1, delete "or claim";

line 2, delete "2".

Claim 6, line 3, change "any one of claims 1 to 5" to --claim 1--.

### REMARKS

By this Preliminary Amendment, claims 7-9 have been canceled, and claims 3, 4, 5, and 6 have been amended to eliminate the multiple dependent claims. Entry of this Preliminary Amendment is respectfully requested.

Respectfully submitted,

JONES VOLENTINE, LLC

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Date: November 3, 2000

### "Gas Generation System"

Industrial demands for alternative process gases for dry (plasma and non-plasma) process systems has led to the investigation of a number of different chemistries.

5 Several different highly-reactive halogen-based chemistries are known to be likely candidates to achieve an improved process capability including etch rate, selectivity etc.

Gases in this category include pure-halide (inter-halogenated and molecular halogen) compounds and suffer from increased cost (of the delivery and abatement system as well as precursor itself), greater health and safety risks, transportation difficulty (and cost) as well as relatively poor commercial availability.

According to the invention there is provided a gas
15 generator system comprising supply sources for halogenated
gases, including pure molecular halogens, connected into a
gas reaction chamber or chamber system enabling generation
of a predetermined gas for localised use in a subsequent
process.

In the preferred arrangement the reaction chamber has a valved outlet for direct supply of the generated gas to a single or multiple chamber processing tool or process chamber.

"Localised" (or point of use) means that the delivery
system is located near to a process chamber or a number of
chambers or number of systems near to one another, so that
the gases created can be delivered directly to the chamber

or system for immediate use rather than being created offsite and transported in a suitable container for subsequent introduction into the apparatus.

More than one generator may be used for each process 5 chamber.

In one embodiment, this invention will provide for the localised generation of reactive process gases. These can be generated local to each process tool through the direct combination of different precursor gases under controlled temperature and pressure reaction conditions. Various inter-halogen and compound halogenated gases can be generated in this way. This system can include a feedback system to precisely control the precursor that is being generated.

A second embodiment of this invention will provide for
the local on-board synthesis of reactive precursors for
plasma and non-plasma processing which include precursors
which would otherwise not be readily available due to
instability or short-lifetime or difficulty in commercial
manufacture or supply. This allows for the direct synthesis
and reactive investigation of new groups of halide precursors for semiconductor or non-semiconductor processing.

A third embodiment of this invention provides for the synthesis of precursors that replace directly or indirectly (by simulating the behaviour) the gases that are either in use or have been used in industry and are subject to restriction in use or withdrawal by new environmental

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legislation. The Montreal Protocol defines environmentally unfriendly chemicals including those that have already been restricted or those that will be restricted in application in the near future. This will impact on the availability of the gases as production is restricted and also on the increasing necessity for abatement during even limited use. Indeed, much recent work has focused on the search for suitable alternative replacement gases (Fracassi and d'Agostino, J.Vac.Sci.Technol.B 16(4), Jul/Aug. 1998). With suitable abatement means, the synthesis of the material on demand may well be an acceptable means of continuing to use existing chemistries. Commercially this may be the only one of a few solutions available.

The invention further extends to a method of generating gases for localised use in a subsequent process by utilising the system of this invention as defined hereinbefore and using the gas so generated directly in the subsequent process.

The direct combination gas generator can produce a gas

20 in the process chamber by reacting suitable precursor gases
possibly with other materials that may be preloaded within
a temperature and pressure controlled reaction chamber that
is local to a processing tool or chamber. The precursor
gases may not react with the substrate being processed, or

25 indeed be desired in the processing tool individually. The
design of the system avoids the occurrence in the
processing tool or chamber of any possible adverse

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reactions, during the combination of the precursor gases, that might otherwise prejudice the overall process. Bypass of the process chamber to an abatement tool inhibits the pre-reaction gas mixture from adversely influencing the process in the process chamber. The precursor gases are redirected into the process chamber by the process controller after the required flow and composition has stabilised or wafer loading is complete. The bypass function may also be used during wafer transfer to maintain constant supply quality and conditions.

The precursors for the reaction chamber include any of the following qases:-

- 1. at least one halogen selected from  $F_2$ ,  $Cl_2$ ,  $Br_2$ ,  $I_2$  as the required halogen source;
- additional gases from N<sub>2</sub>, H<sub>2</sub>, O<sub>2</sub>;
  - 3. additional gases from He, Ar, Kr, Xe.

The generator may further comprise any one or more of the following components:-

- electrode materials selected from C, B, S, Si, Ge, P in either elemental or appropriate compound form. Where appropriate, the electrode material may be porous to increase the surface reaction area. Metal-containing electrodes may also be used. The electrodes may be independently temperature controlled and electrically and/or magnetically biased;
- 2. appropriate catalysts (product generation depend-

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ent):

- gas analysers such as infra-red spectroscopes and/or mass spectrometers;
- 4. a feedback control system which senses the output gas and adjusts reaction parameters (gas flow rates, temperatures, pressure etc) to achieve the desired output concentration;
- 5. an appropriate reaction vessel or chamber. A number of chambers may be used in series and/or parallel to generate precursors requiring more complex generation mechanisms:
- an appropriate vacuum control system, valving and gauging, including means for bypassing and purging;
- an appropriate abatement system.

The generator can operate within the following temperature and pressure range: room temperature to several hundred degrees C at several Torr to atmospheric pressure. In particular the reaction chamber may be operated at or 120 near atmospheric pressure, going up the range from several Torr to 760 Torr. The reaction chamber temperature can be controlled at between ambient room temperature up to 800°C generally, but probably will lie within the range of 100 - 500°C. Differing temperatures may be maintained in at least 2 separate zones of the reaction chamber system. For certain processes, elements of the system may be below room temperature for product purity control. The temperature

control of any electrode may be separate from the vessel and the electrode may be independently biassed either electrically and/or magnetically. This or other biassing means may be used to generate a plasma.

5 The supply to the gas reaction generator of high purity gases removes the need to polish the generated gas to remove unwanted impurities before passing into the process chamber. Mass flow controllers may be used to precisely meter the flow of the supply gases.

The valved control of the flow into the process chamber (if necessary augmented by a control system) ensures that the generator does not experience the low pressure (vacuum) at the process chamber. The preferred method of production of fluorine is by fluoride molten 15 electrolytic generators which can be installed locally to the tool and overcomes the need to obtain high purity 100% fluorine in cylinders. Other means of F, generation can be appropriately used. The preferred method of supply of Cl, is from either an electrolytic generator or from high-pressure 20 cylinders, both of which are readily available. Similarly, appropriate sources of Br,, I, may be used.

Multiple or singular gas inlets and/or either two or more electrodes (or a single composite electrode) necessary may be used to generate some of the more complex 25 halide species. Electrodes within the reaction chamber may be electrically and/or magnetically biased.

The reaction chamber can be formed from high purity

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materials (such as those sold under the Trade Marks Monel
 (nickel/copper/iron alloy), Inconel (nickel/chromium/iron
 alloy) and Hastalloy (nickel/molybdenum/chromium/manganese
 /iron alloy)) which would not be financially feasible with
5 large scale generation systems

The concept of local generation allows the production of the desired process gases to a high purity, although the specific reaction products may be a family of compounds not just one specific product. This can be achieved at a 10 reasonable cost and low risk. The addition of this gas generator, feeding a process tool, allows a novel capability to introduce different generated process gases into the process chamber where, for many different reasons, the option of using the gas directly would not be possible.

The gas generator is able to provide a local supply of various gases on demand, such as :-

- Inter-halogen compounds including Cl<sub>x</sub>F<sub>y</sub>, F<sub>x</sub>Br<sub>y</sub>,
  Cl<sub>x</sub>Br<sub>y</sub> and F<sub>x</sub>Cl<sub>y</sub>Br<sub>z</sub> (where <sub>x y</sub> and <sub>z</sub> are integers).
   An I<sub>2</sub> source could also be added to provide additional I-containing compound halogens;
- Groups of halide precursors for plasma and nonplasma processing which include precursors which would otherwise be unavailable due to instability or short-lifetime or difficulty in commercial manufacture or supply;
- 3. Freons or halo-carbides including  $C_xF_y$ ,  $C_wF_xCl_y$ ,  $C_wF_xCl_yF_x$ ,  $C_wF_xCl_yF_x$ ,  $C_wCl_xF_x$ ,  $C_wCl_xF_x$ ,  $C_wCl_xF_x$ ,  $C_wF_xF_x$ ,  $C_wF_xF_x$

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(where  $_{\rm w,~x,~y}$  and  $_{\rm z}$  are integers). An I $_{\rm 2}$  source could also be added to provide additional I-containing halo-carbides;

- Other reactive halides where the C is replaced by N or B;
  - Other reactive halides where any C is replaced by combination of C with N, B and/or H;
  - 6. Metal halides, where the C source is replaced by an appropriate metal-containing electrode, (including W, Mo, Ti and Ta);
  - Halide complexes of any combination of the groups listed in 3.4.5 and 6 above.

Ideal gases for generation include C1F, C1F<sub>3</sub>, C1F<sub>5</sub>, BrF<sub>3</sub>, WF<sub>6</sub>, MoF<sub>6</sub>, TiF<sub>4</sub>, TiCl<sub>4</sub>, TaF<sub>5</sub>, BrF, CF<sub>4</sub>, C<sub>2</sub>F<sub>6</sub>, C<sub>3</sub>F<sub>8</sub>, CHF<sub>3</sub>, 15 CF<sub>2</sub>H<sub>2</sub>, CCl<sub>2</sub>F<sub>2</sub>, CCl<sub>4</sub>, CF<sub>3</sub>Br and NF<sub>3</sub>, and related compounds. An appropriate selection of precursors can also be used to synthesise or generate organo-metallic compounds

The generator of the invention offers many advantages over direct gas delivery. For some of the gases the reaction gas generator can operate at or near atmospheric pressure, thereby eliminating the need for high-pressure regulators on the system. Installation and storage of hazardous gases is reduced. The local generation, on demand, of the hazardous gases eliminates long (and usually high-pressure) gas lines from a central store to the installation and minimises associated safety risks. There would be a significant reduction in the installation costs

10 regulatory devices.

due to the reduced level of plumbing of additional gases and the associated safety requirements. The maintenance of the complete system is eased by the absence of any of the generated gases when the system is not operating. The 5 quantity of the generated gases can be regulated to that required for the specific application so that the gas consumption is optimised and excess generated gas avoided. Some gases may require higher generation pressures (above atmospheric) and hence necessitate the use of pressure

The invention may be performed in various ways and preferred embodiments thereof will now be described, by way of example, with reference to the accompanying drawings, in which:-

15 Figure 1 is a diagrammatic illustration of a general gas generation system of this invention;

Figure 2 indicates various input and control features of the system of Figure 1;

Figure 3 shows a modified system for that indicated in 20 Figure 2; and

Figures 4, 5 and 6 illustrate still further modifications of the general gas generation system illustrated in Figure 1.

In the arrangement shown in Figure 1 precursor gases
25 are passed from suitable supply sources 1 and 2 to a
reaction chamber 3 where the gases are combined under
controlled conditions. The reaction product is then fed to

a process chamber 4 where a dry process utilising that gas is to take place. Appropriate valving will include valves provided at A, B, C and D for appropriate control and isolation means. Linked control systems 5 and 6 monitor 5 and maintain the supply to and the conditions in the chambers 3 and 4.

From the process chamber 4 gases pass to an exhaust system 7, which in turn leads to an abatement tool 8 (which is usually needed). A bypass outlet 9 leads from the 10 reaction chamber 3 to the exhaust system, whereby gases can be switched into the process chamber only when required for processing. This also allows the means for ensuring stable gas composition and flow to be maintained prior to switching into the process chamber.

15 Figure 2 shows features of the reaction chamber 3, and connections thereto, in greater detail. This illustrates inlets 1A and 2A from sources 1 and 2 and another inlet 10 for a third precursor gas (there could be still further inlets if required). A control system 11 (which is a 20 single system but for clarity is shown in two parts 11 and 15) can take measurements from analysis devices 12 and 13 and a pressure-measuring device 14. The control system 15 can take measurements from a temperature measurement device 16 and also provide control for an auto pressure control device 17 and a temperature control device 18. Optionally an electrode 19 can be provided within the reaction chamber 3 with biassing means (not shown) and a temperature control

device (not shown).

Figures 3, 4, 5 and 6 illustrate various ways in which electrodes can be incorporated into the reaction chamber 3 (which in turn may comprise a single chamber or a combina-5 tion of chambers linked in serial or parallel or any desired combination thereof). In Figure 3 the chamber 3 is shown as being provided with a porous electrode 20. Figure 4 illustrates a two chamber system wherein the preliminary reaction chamber 3A incorporates a normal electrode 21 10 whilst a downstream chamber 3B incorporates a porous electrode 22. The third gas supply line 10 is connected to this secondary chamber 3B. In Figure 5 three linked and 3C are shown, each reaction chambers 3A, 3B incorporating a standard electrode 23, 24 and 25 with 15 respective gas supply sources 3, 4 and 10. In the modified arrangement shown in Figure 6 the chambers 3A, 3B and 3C are modified to incorporate porous electrodes 23A, 24A and 25A.

The procedures of this invention are particularly

20 useful additionally as a method of local creation of a

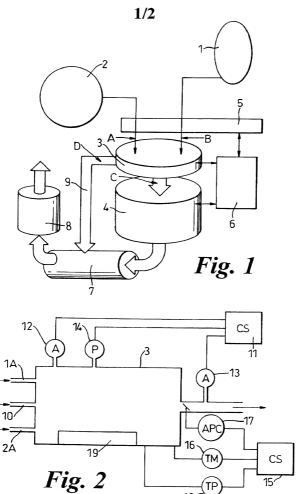
number of short shelf-life organo-metallic compounds using
suitable precursors.

#### CLAIMS

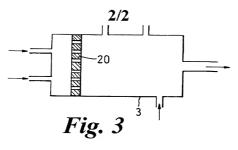
- A gas generator system comprising supply sources for halogenated gases, including pure molecular halogens, connected into a gas reaction chamber or chamber system
   enabling generation of a predetermined gas for localised use in a subsequent process.
- 2. A gas generator system as claimed in claim 1, wherein the reaction chamber has a valved outlet for direct supply of the generated gas to a process chamber or a single or 10 multiple chamber processing tool or tools.
  - A gas generator system as claimed in claim 1 or claim
     which provides for the localised generation of reactive process gases.
  - 4. A gas generator system as claimed in claim 1 or claim
- 2, which provides for the local synthesis of reactive precursors for plasma and non-plasma processing which include precursors which would otherwise not readily available due to instability or short-lifetime or difficulty in commercial manufacture or supply.
- 20 5. A gas generator system as claimed in claim 1 or claim 2, which provides for the synthesis of precursors that replace directly or indirectly (by simulating the behaviour) the gases that are either in use or have been used in industry and are subject to restriction in use or 25 withdrawal by environmental legislation.
  - 6. A method of generating gases for localised use in a subsequent process by utilising the system as defined in

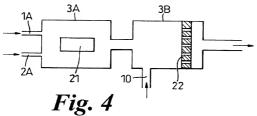
any one of claims 1 to 5 and using the gas so generated directly in the subsequent process.

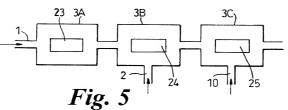
- 7. A gas generator system according to claim 1 and substantially as herein described.
- 5 8. A method of generating gases according to claim 6 and substantially as herein described.
  - 9. Any novel combination of a gas generator or a process for generating gases and with reference to the accompanying drawings.

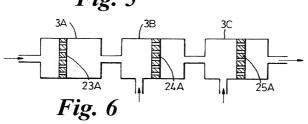


SUBSTITUTE SHEET (RULE 26)









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JONES VOLENTINE, L. L. C. (6/2000)

## DECLARATION AND POWER OF ATTORNEY FOR U.S. PATENT APPLICATION

(X) Original ( ) Supplemental ( ) Substitute ( ) PCT (	) Design
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As a below named inventor, I hereby declare that: my residence, post office address and citizenship are as stated below next to my name; that I verily believe that I am the original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural inventors are named below) of the subject matter which is claimed and for which a patent is sought on the invention entitled:

#### TITLE: GAS GENERATION SYSTEM

of which is desc	ribed and claimed in:	
( ) the	attached specification, or	
( ) the	specification in the application Serial No	filed,
	and with amendments through	(if applicable), or
(X) the	specification in International Application No. PCT/	GB00/00793 , filed 6 MARCH 2000 ,
	and as amended on	_ (if applicable).

I hereby state that I have reviewed and understand the content of the above-identified specification, including the claims, as amended by any amendment(s) referred to above.

I acknowledge my duty to disclose information of which I am aware which is material to the examination of this application in accordance with Title 37, Code of Federal Regulations, §1.56(a).

I hereby claim foreign priority benefits under Title 35, United States Code, §119 (and §172 if this application is for a Design) of any foreign application(s) for patent or inventor's certificate listed below and have also identified below any foreign application for patent or inventor's certificate having a filing date before that of the application on which priority is claimed:

COUNTRY	APPLICATION NO.	DATE OF FILING	PRIORITY CLAIMED
GREAT BRITAIN	9904925.6	4 MARCH 1999	YES
GREAT BRITAIN	9909853.5	29 APRIL 1999	YES
		-	

I hereby claim the benefit under Title 35, United States Code, §120 of any United States application(s) the below and, insofar as the subject matter of each of the claims of this application is not disclosed in the prior United States application in the manner provided by the first paragraph of Title 35, United States Code, §112, I acknowledge the duty to disclose material information as defined in Title 37, Code of Federal Regulations, §1.56(a) which occurred between the filing date of the prior application and the national or PCT international filing date of this application:

APPLICATION SERIAL NO.	U.S. FILING DATE	STATUS: PATENTED, PENDING, ABANDONED
	•	

And I hereby appoint Raymond C. Jones, Reg. No. 34,631 and Adam C. Volentine, Reg. No. 33,289, of the firm of JONES VOLENTINE, L.L.C., jointly and severally, attorneys to prosecute this application and to transact all business in the U.S. Patent and Trademark Office connected therewith.

I hereby authorize the U.S. attorneys named herein to accept and follow instructions from <u>WYNNE-JONES LAINE</u> <u>& JAMES</u> as to any action to be taken in the U.S. Patent and Trademark Office regarding this application without direct communication between the U.S. attorneys and myself. In the event of a change in the persons from whom instructions may be taken, the U.S. attorneys named herein will be so notified by me.

Kindly direct all correspondence to:

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Full Name of 4th Inventor	FAMILY NAME	FIRST GIVEN NAME	SECOND GIVEN NAME
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Post Office Address	ADDRESS	СІТУ	STATE OR COUNTRY ZIP CODE
Full Name of 5th Inventor	FAMILY NAME	FIRST GIVEN NAME	SECOND GIVEN NAME
	PAMILY NAME  CITY	FIRST GIVEN NAME	SECOND GIVEN NAME  COUNTRY OF CITIZENSHIP

I further declare that all statements made herein of my own knowledge are true, and that all statements on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

application or any patent	issuing thereon.		
lst Inventor Voti K	fron BHARDWAJ	Dat	e 23°d Octobe 2000.
2nd Inventor		Dat	e
3rd Inventor		Da	te
4th Inventor		Da	te
5th Inventor	W. A. W. C.	Da	te
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nnlicant Reference No	STS 32	Atty Docket No.:	WLJ.059